

# H1M065B050/T050

Silicon Carbide MOSFET  
N-CHANNEL ENHANCEMENT MODE

## Features

- Low On-Resistance and High Current Density
- Low Capacitance for High Frequency Operation
- Ultra-high Avalanche Ruggedness
- Positive Temperature Coefficient Device
- AEC-Q101 Qualified
- RoHS Compliant and Halogen Free

## Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Capable of 175°C High  $T_j$  Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems

## Applications

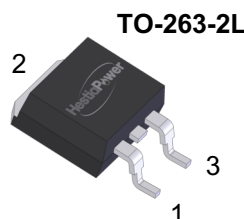
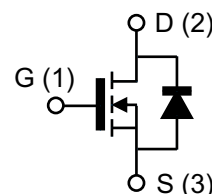
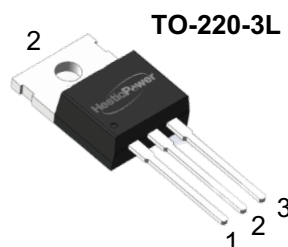
- Switching Mode Power Supply
- DC/DC Converters, UPS, and PFC
- EV Charging Station
- Motor Drives
- Power Inverters
- Solar/Wind Renewable Energy

## Product Summary

$V_{DS}$	650V
$I_D(@25^\circ\text{C})$	54A
$R_{DS(on)}$	50mΩ



## Circuit Diagram



Part Number	Package	Marking
H1M065B050	TO-220-3L	H1M065B050
H1M065T050	TO-263-2L	H1M065T050

## Absolute Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	$V_{DS, max}$	$V_{GS}=0V, I_D=100\mu A$	650	V
Continuous Drain Current	$I_D$	$V_{GS}=20V, T_c=25^\circ\text{C}$	54	A
		$V_{GS}=20V, T_c=110^\circ\text{C}$	36.5	
Pulse Drain Current	$I_{D, pulse}$	$t_{PW}$ limitation per Fig.15	123.5	
Avalanche energy, Single Pulse	$E_{AS}$	$V_{DD}=100V, I_D=10A$	1250	mJ
Power Dissipation	$P_D$	$T_c=25^\circ\text{C}$	197	W
Recommend Gate Source Voltage	$V_{GS, op}$	Static, recommended DC operating values	-5 to 20	V
Maximum Gate Source Voltage	$V_{GS, max}$	Transient operating limit (AC $f > 1\text{Hz}$ , duty cycle $< 1\%$ )	-10 to 25	
Junction & Storage Temperature	$T_j, T_{stg}$		-55 to 175	$^\circ\text{C}$
Soldering Temperature	$T_L$		260	
Mounting Torque	$M_D$	M3 or 6-32 screw (for TO-220)	1.0	Nm

## Thermal Resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction to Case	$R_{\theta, JC}$		0.76		$^\circ\text{C/W}$
Thermal Resistance, Junction to Ambient	$R_{\theta, JA}$				$^\circ\text{C/W}$

## Electrical Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>DS</sub> =100μA	650			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =10V, I <sub>DS</sub> =20mA		2.6		V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V		<1	50	μA
		V <sub>DS</sub> =650V, V <sub>GS</sub> =0V T <sub>j</sub> =175°C		10	500	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V			250	nA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =20V, I <sub>DS</sub> =20A		50	65	mΩ
		V <sub>GS</sub> =20V, I <sub>DS</sub> =20A, T <sub>j</sub> =175°C		65		
Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =15V, I <sub>DS</sub> =40A		13.2		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V f =1MHz, V <sub>AC</sub> =25mV		1850		pF
Output Capacitance	C <sub>oss</sub>			208		
Reverse Transfer Capacitance	C <sub>rss</sub>			33		
Effective Output Capacitance, Energy Related	C <sub>o(er)</sub>		V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 400V		237	
Effective Output Capacitance, Time Related	C <sub>o(tr)</sub>	I <sub>D</sub> =const., V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 400V		305		
Short-Circuit Withstand Time	t <sub>SC</sub>	V <sub>GS</sub> =0/15V, V <sub>DS</sub> =400V R <sub>G</sub> =100Ω		<18		μs
Turn On Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =-4/+20V, I <sub>D</sub> =20A, R <sub>L</sub> =20Ω, R <sub>G(ext)</sub> = 2.7 Ω		16		ns
Rise Time	t <sub>r</sub>			17		
Turn Off Delay Time	t <sub>d(off)</sub>			20		
Fall Time	t <sub>f</sub>			10		
C <sub>oss</sub> Stored Energy	E <sub>oss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V f =1MHz, V <sub>AC</sub> =25mV		24		μJ
Turn-on Switching Energy	E <sub>on</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =0/20V, I <sub>D</sub> =20A,		21*		
Turn-off Switching Energy	E <sub>off</sub>	R <sub>G(ext)</sub> = 2.7 Ω		28*		
Internal Gate Resistance	R <sub>G(int.)</sub>	f =1MHz, V <sub>AC</sub> =25mV		1.2		Ω

\*Based on the results of calculation, note that the energy loss caused by the reverse recovery of free-wheeling diode is not included in E<sub>on</sub>.

## Built-in SiC Diode Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Typ.	Unit
Inverse Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>SD</sub> =5A	3.0	V
Continuous Diode Forward Current	I <sub>S</sub>	V <sub>GS</sub> =-5V, T <sub>C</sub> =25°C	32	A
Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> =0V,	58	ns
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>SD</sub> =30A, V <sub>DS</sub> =400V,	122	nC
Peak Reverse Recovery Current	I <sub>rrm</sub>	di/dt=300A/μs	3.75	A

## Gate Charge Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Gate to Source Charge	Q <sub>GS</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =-5/+20V, I <sub>D</sub> =30A	30	nC
Gate to Drain Charge	Q <sub>GD</sub>		43	
Total Gate Charge	Q <sub>G</sub>		121	
Gate plateau voltage	V <sub>pl</sub>		8.8	V

## Typical Device Performance

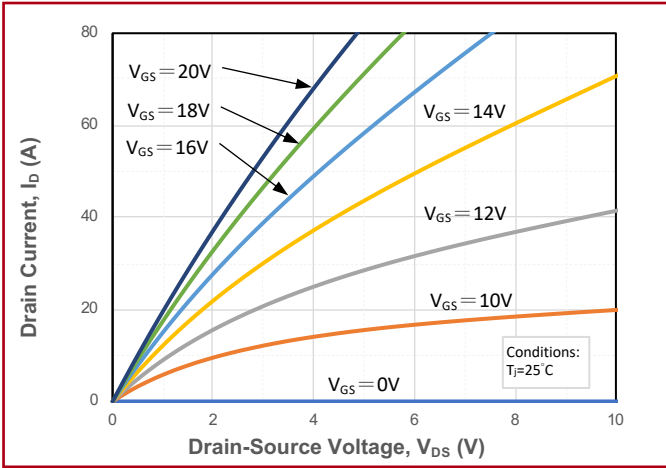


Fig.1 Forward Output Characteristics at  $T_j = 25^\circ\text{C}$

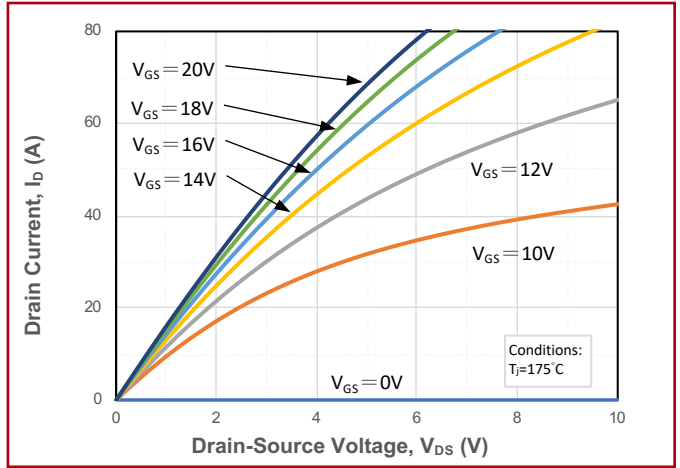


Fig.2 Forward Output Characteristics at  $T_j = 175^\circ\text{C}$

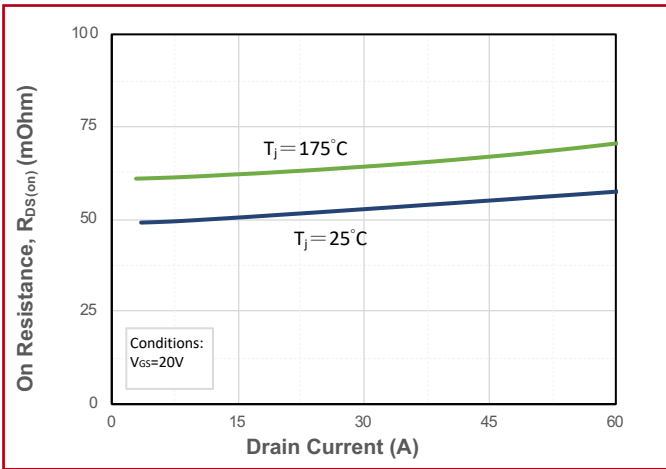


Fig.3 On-Resistance vs. Drain Current for Various  $T_j$

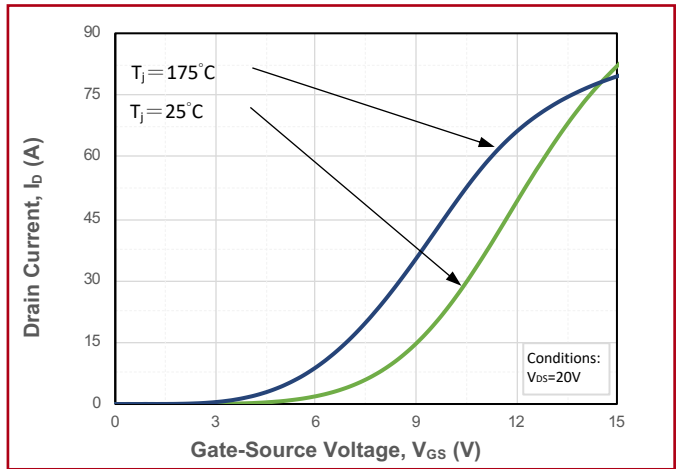


Fig.4 Transfer Characteristics for Various  $T_j$

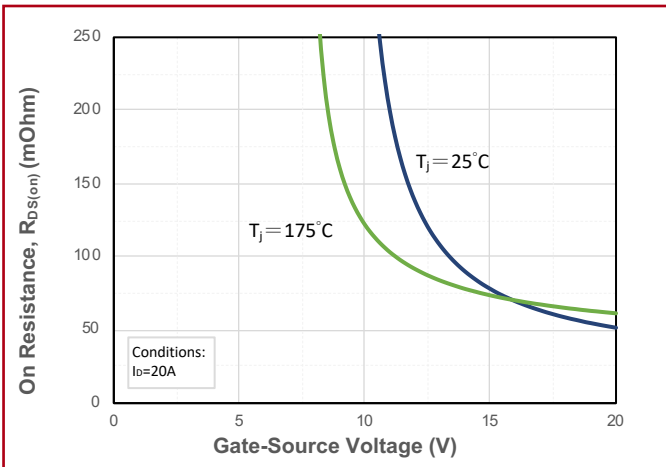


Fig.5 On-Resistance vs. Gate Voltage for Various  $T_j$

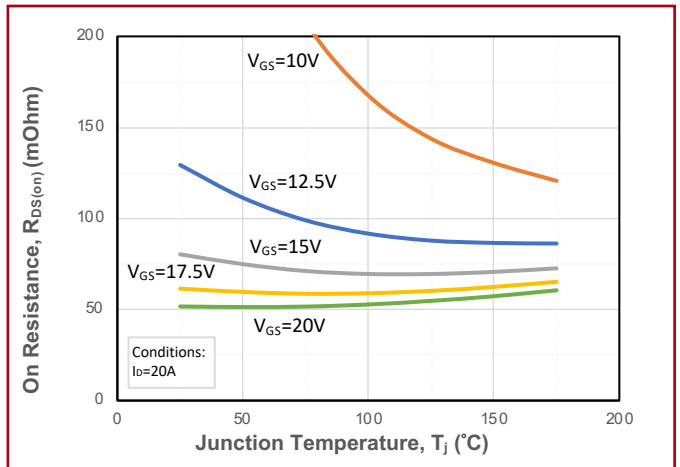
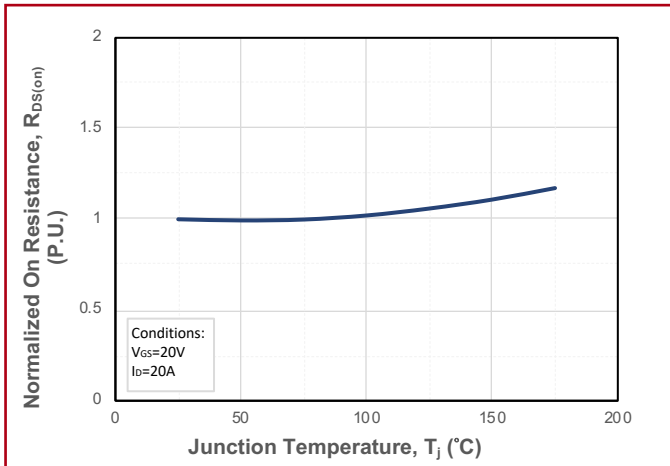
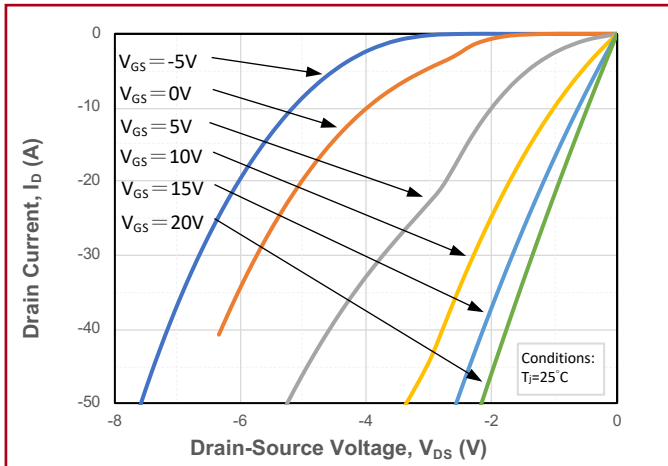


Fig.6 On-Resistance vs. Temperature for Various Gate Voltage

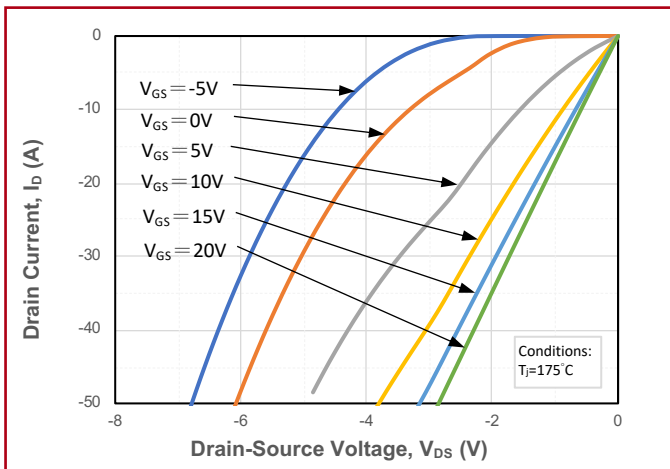
## Typical Device Performance



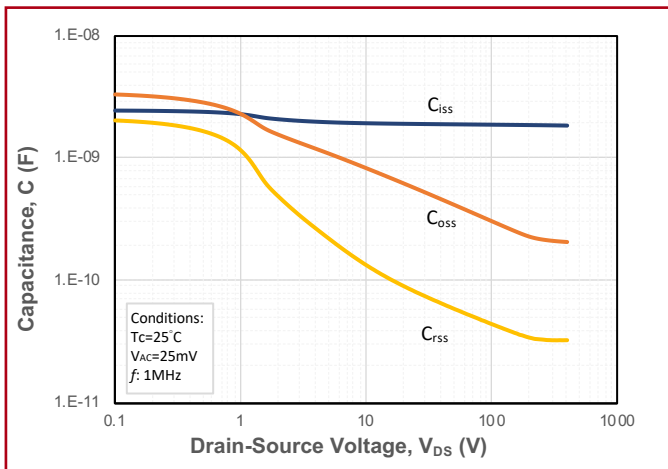
**Fig.7** Normalized On-Resistance vs. Temperature



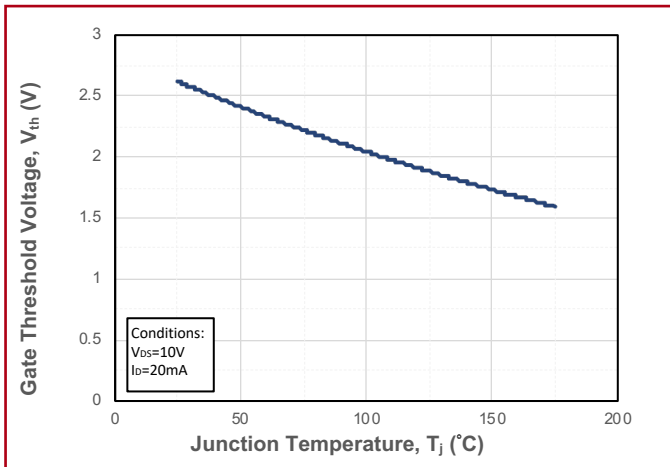
**Fig.8** Reverse Output Characteristics at  $T_j = 25^\circ C$



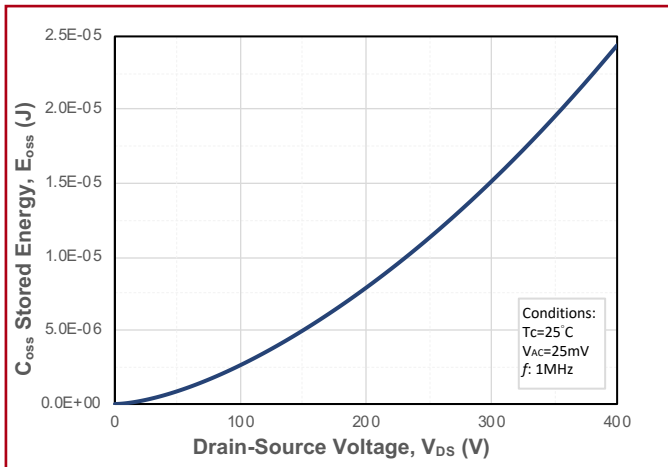
**Fig.9** Reverse Output Characteristics at  $T_j = 175^\circ C$



**Fig.10** Capacitances vs. Drain to Source Voltage

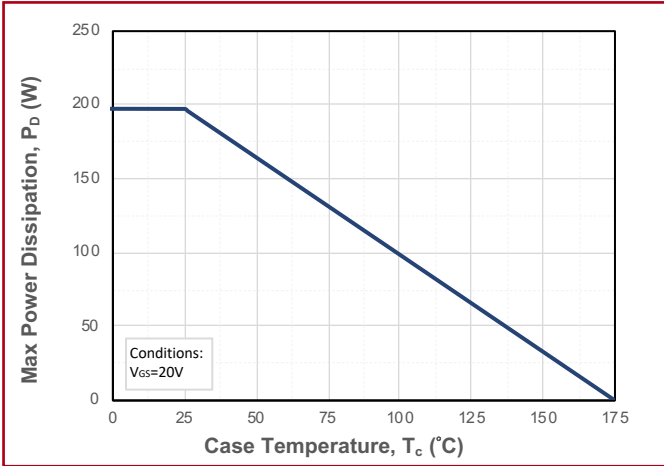


**Fig.11** Threshold Voltage vs. Temperature

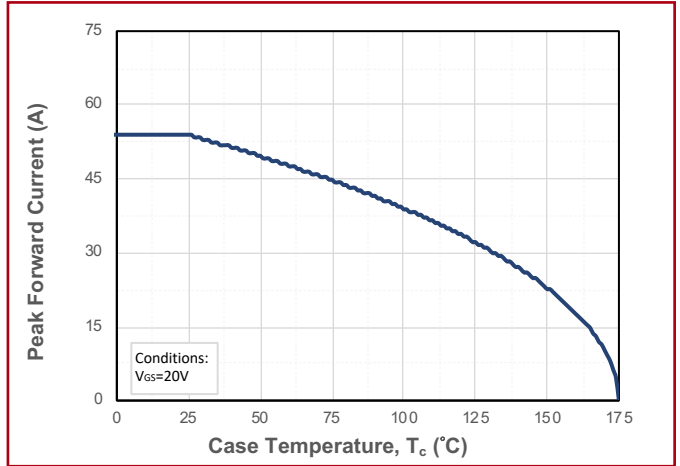


**Fig.12** Output Capacitor Stored Energy

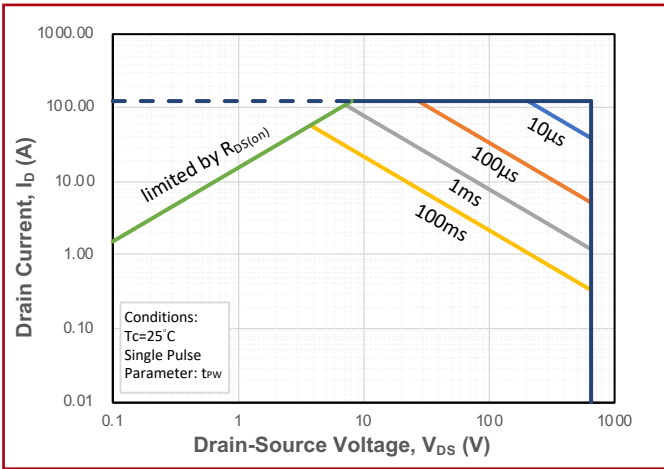
## Typical Device Performance



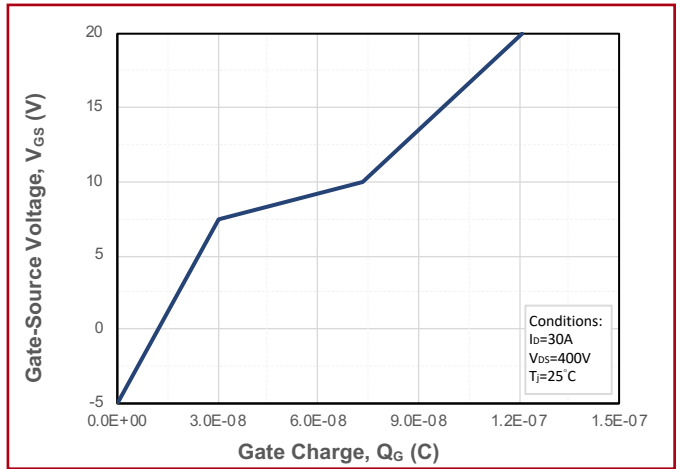
**Fig.13 Maximum Power Dissipation Derating vs. Case Temperature**



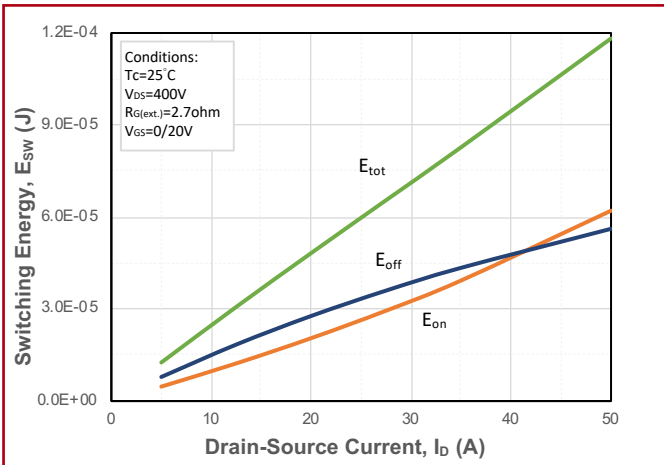
**Fig.14 Drain Current Derating vs. Case Temperature**



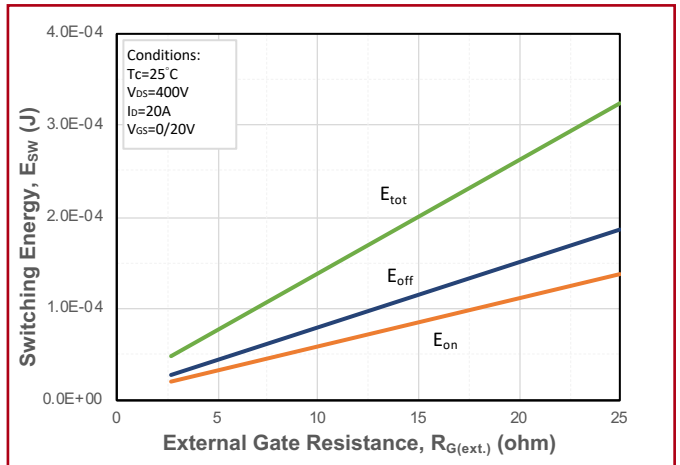
**Fig.15 Safe Operating Area**



**Fig.16 Gate Charge Characteristics**



**Fig.17 Clamped Inductive Switching Energy vs. Drain Current**



**Fig.18 Clamped Inductive Switching Energy vs. External Gate Resistor ( $R_{G(ext.)}$ )**

## Typical Device Performance

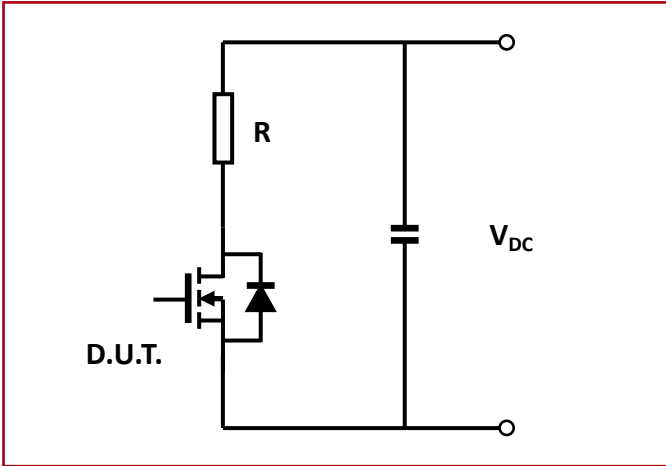


Fig.19 Schematic of Resistive Switching

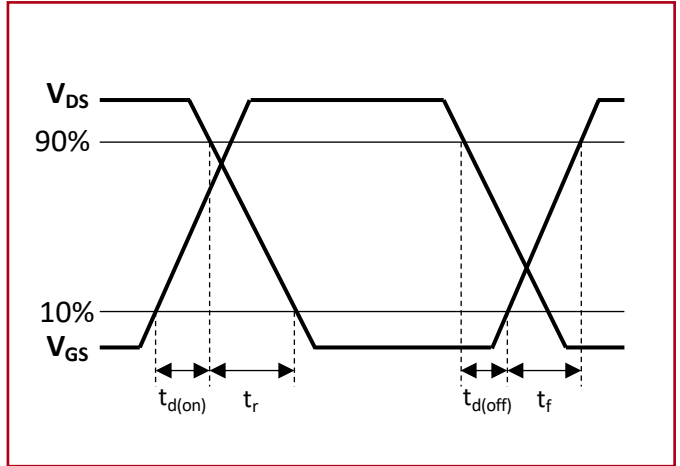


Fig.20 Switching Times Definition

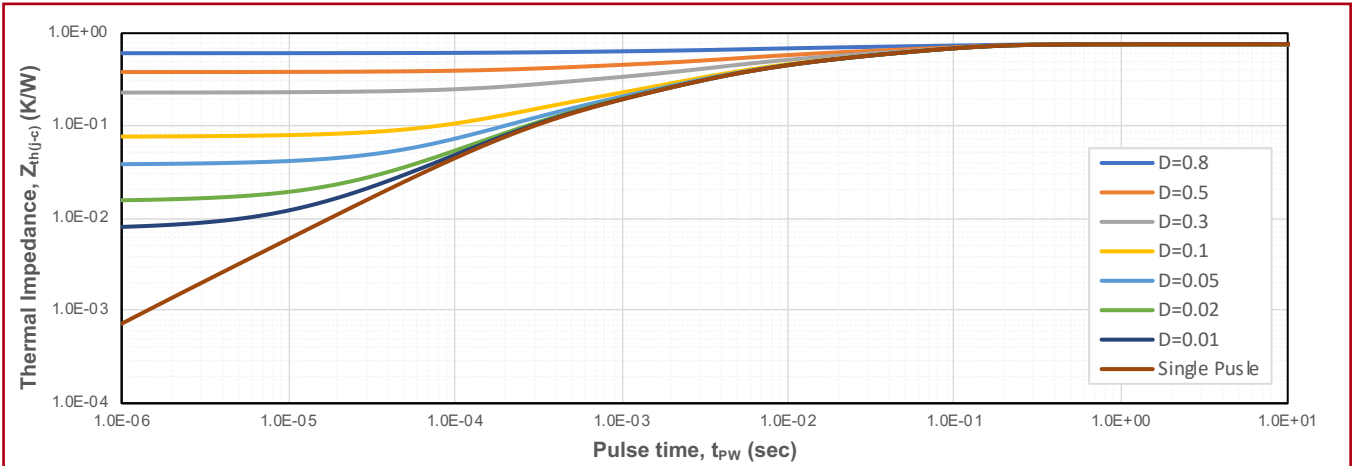


Fig.21 Transient Junction to Case Thermal Impedance

### Naming Rule

**H1 M 065 B 050**

#### Generation

H1 = Gen 1<sup>st</sup> Discrete

#### Device Type

M = MOSFET    J = JMOS

S = JBS diode

#### Breakdown Voltage

065 = 650V    170 = 1700V

120 = 1200V    330 = 3300V

#### Package

F = TO-247-3L    B = TO-220-3L

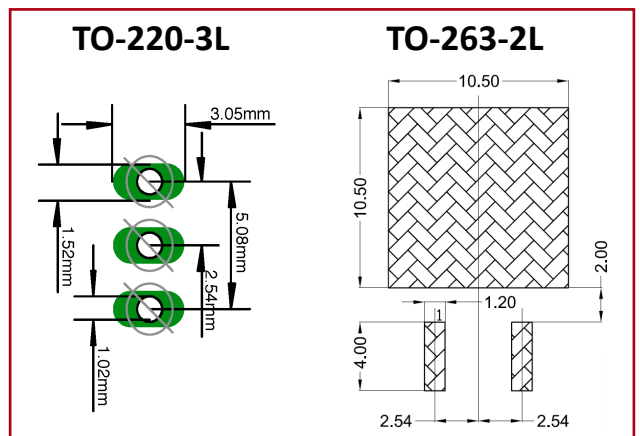
T = TO-263-2L    N = Bare Die

#### Typical On-Resistance

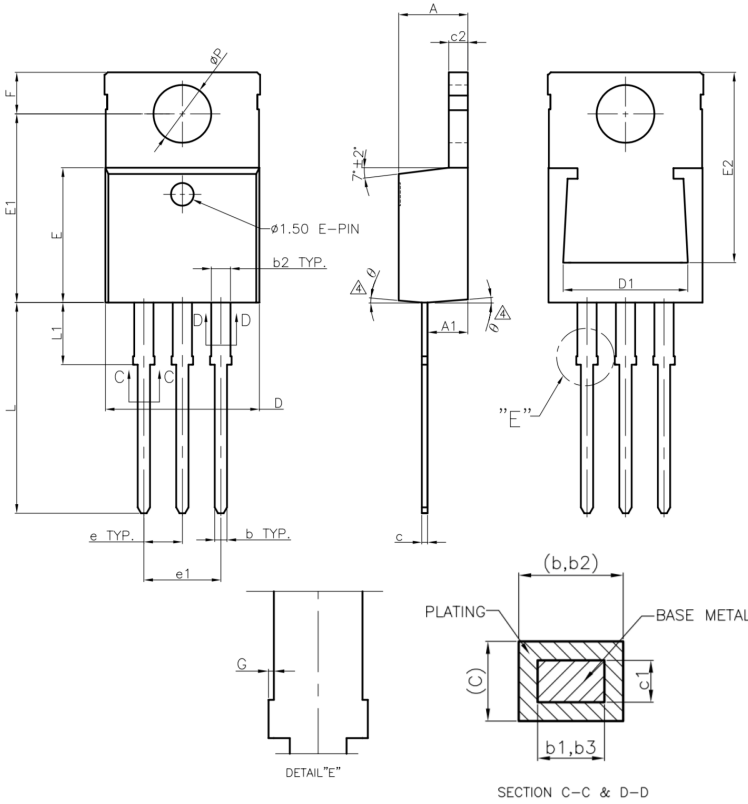
020 = 20mΩ    050 = 50mΩ    100 = 100mΩ

200 = 200mΩ

### Recommended Solder Pad Layout

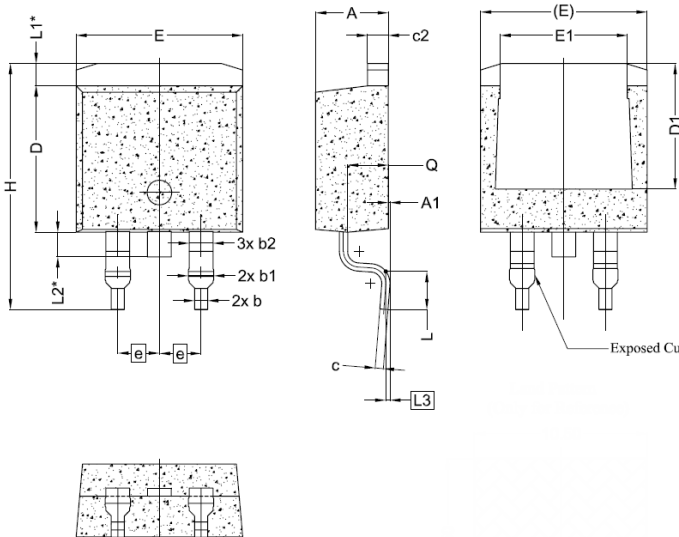


### Package Dimensions (TO-220-3L)



Symbol	mm		
	Min.	Typ.	Max.
A	4.470	-	4.670
A1	2.520	-	2.820
b	0.711	0.813	0.910
b1	0.711	-	0.914
b2	1.170	1.270	1.370
b3	1.168	-	1.372
c	0.279	0.381	0.483
c1	0.279	-	0.432
c2	1.168	1.270	1.370
D	10.010	-	10.310
D1	7.595	-	8.230
E	8.763	8.890	9.017
E1	12.294	12.446	12.586
E2	11.913	-	12.548
e	2.540 BSC		
e1	4.980	-	5.180
F	2.642	2.743	2.946
G	0.000	-	0.152
L	13.700	-	14.100
L1	3.980	4.107	4.230
$\phi P$	3.770	-	3.890
$\theta$	1°	-	5°

### Package Dimensions (TO-263-2L)



Symbol	mm		
	Min.	Typ.	Max.
A	4.24	4.44	4.64
A1	0.00	0.10	0.25
b	0.70	0.80	0.90
b1	1.20	1.55	1.75
b2	1.20	1.45	1.70
c	0.40	0.50	0.60
c2	1.15	1.27	1.40
D	8.82	8.92	9.02
D1	6.86	7.65	---
E	9.96	10.16	10.36
E1	6.89	7.77	7.89
e	2.54 BSC		
e1	5.08 BSC		
H	14.61	15.00	15.88
L	1.78	2.32	2.79
L1	1.36 REF.		
L2	1.50 REF.		
L3	0.25 BSC		
Q	2.30	2.48	2.70

Note:

- All Dimensions Are In mm.
- Dimension D & E Do Not Include Mold Flash. Mold Flash Shall Not Exceed 0.127mm Pre Side. These Dimensions Are Measured At The Outermost Extreme Of The Plastic Body.
- Thermal Pad Contour Optional Within Dimensions E, L1, D1 & E1.
- Dimension D1 & E1 Establish A Minmum Mounting Surface for The Thermal Pad.
- "\*" is reference .

\*The information provided herein is subject to change without notice.